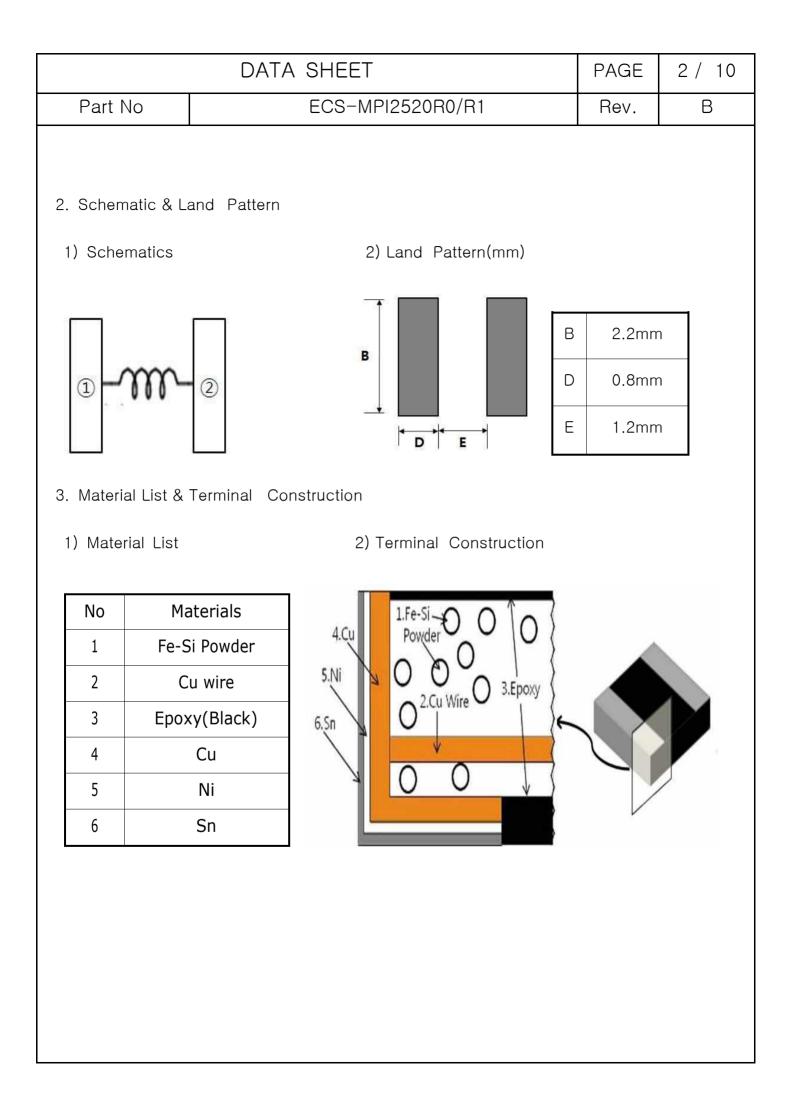
<u>Rev. : B</u> DATE : DEC. 15. 2017

ECS-MPI2520

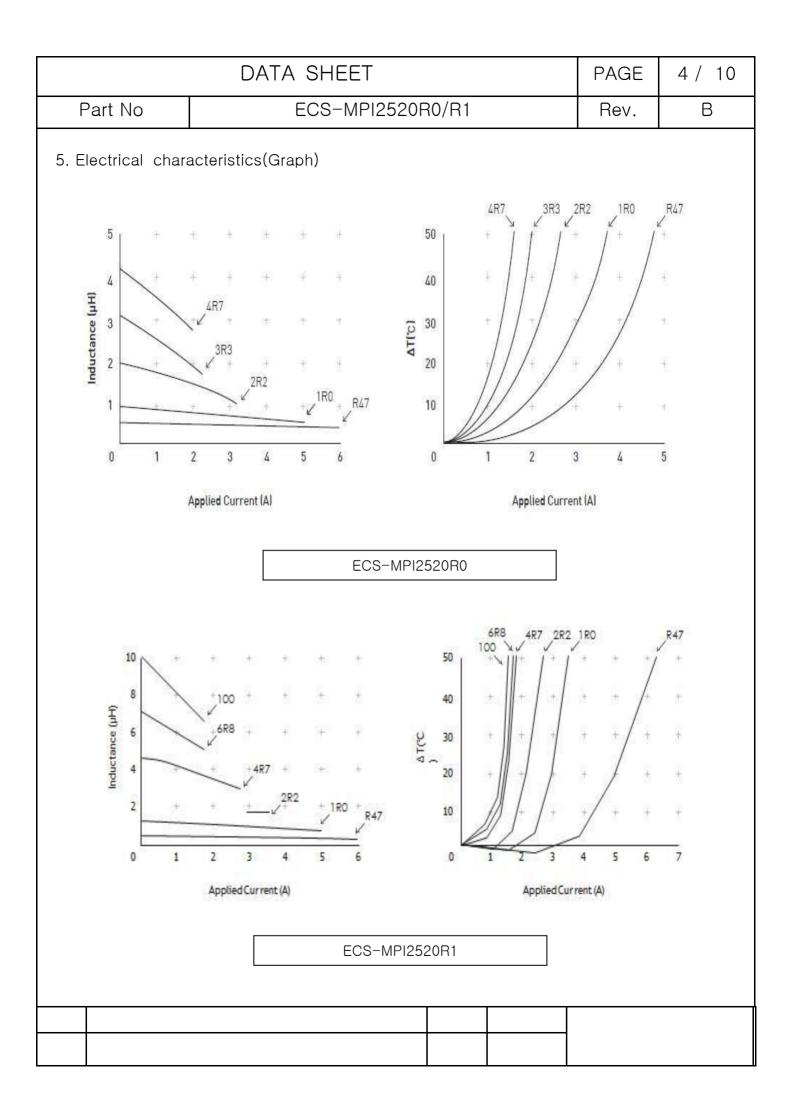
SMD Power Inductor



		DATA SH	HEET		PAG	ie 1	/ 10		
	Part No	art No ECS-MPI2520R0/R1							
	Shape and Dim Shape	nension(mm)							
2)	Dimensions(mm)								
		Top view	Side view	Bottom view					
		B A	→ + _ +		В				
	Item	A(mm	B(mm)	C(mm)		D(mm)			
	ECS-MPI2520R0 ECS-MPI2520R1	2.5 ± 2.5 ±	2.0 ± 0.2 2.0 ± 0.2	1.0 max 1.2 max		6 ± 0.25 6 ± 0.25			
		Revision Hi			Write	Review	Approval		
NO		Note	3101 y	Date	VIIIC	11601600			
1		Initial Release		2017.6.01					
2	Re	evised height indicator ir	n PN	2017. 12. 15			1		



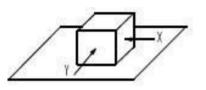
	PAGE	3 / 10									
Part No		ECS	S-MPI2	520R0/R1		Rev.	В				
 4. Electrical Performance 1) Test condition : 1MHz, 0.10V 2) DCR @ 25℃ 											
Part Number	Code Note a	OCL (uH) ± 20% Note b	lsat (A) Note d	Irms (A) Note f	DCR (mΩ) (Typ)	DCR (mΩ) (max) Note g	K-factor				
ECS-MPI2520R0-R47-R	В	0.47	4.4	4.1	28	33.6	2887				
ECS-MPI2520R0-1R0-R	с	0.9	3.2	3.2	50	60	1925				
ECS-MPI2520R0-1R5-R	D	1.5	2.6	2.4	80	96	1444				
ECS-MPI2520R0-2R2-R	E	2.2	2.4	2.2	103	123.6	1283				
ECS-MPI2520R0-3R3-3	F	3.3	1.6	1.6	190	228	1050				
ECS-MPI2520R0-4R7-R	G	4.7	1.4	1.4	240	288	825				
ECS-MPI2520R1-R47-R	A	0.47	4.8	4.5	20	24	2310				
ECS-MPI2520R1-1R0-R	В	1	4	3.7	35	42	1925				
ECS-MPI2520R1-1R5-R	C	1.5	3.4	2.9	55	66	1444				
ECS-MPI2520R1-2R2-R	D	2.2	2.7	2.3	75	90	1255				
ECS-MPI2520R1-3R3-R ECS-MPI2520R1-4R7-R	F	3.3 4.7	2.4 1.9	1.8	105 150	126 180	962 825				
ECS-MPI2520R1-4R7-R	G	4.7 5.6	1.9	1.5	200	240	679				
ECS-MPI2520R1-5R8-R	н	6.8	1.3	1.3	300	360	679				
ECS-MPI2520R1-100-R		10	1.2	1.1	390	468	525				
Measuring Instruments: OCL: <u>HP4284A</u> (Agilent Technologies, or equivalent) DC Bias: <u>HP4284A & HP42841B</u> (Agilent Technologies, or equivalent) DC Resistance: <u>4100ATC</u> (or equivalent) Note a: Print Marking Code on each reel of product to define different part number.											
Note b: Test condition: 1MHz, 0.1V Note c: Test condition: 1 MHz, 0.1V											
Noted: Isat Amperes	Peak for a	approximat	ely 30% F	loll-off (@25	DČ)						
Note f: RMS current temperature of the p				without core	e loss. It is re	commended t	hat the				
Note g: DCR @ 25℃											
					r						



	PAGE	5 / 10	
Part No	ECS-MPI2520R0/R1	Rev.	В

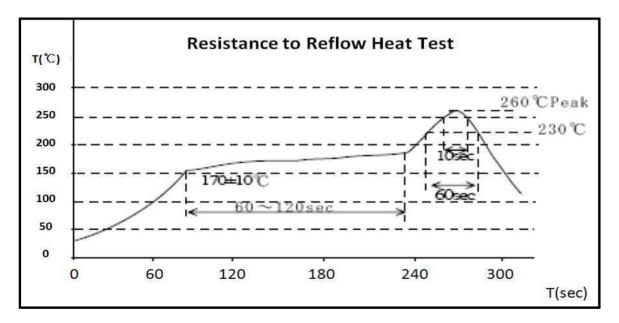
- 6. Mechanical characteristics testing items
- 1) Storage temperature $-40 \sim +105^{\circ}$ C
- 2) Operation Temperature $-40 \sim +105$ °C (Including coil's self-temperature rise)
- 3) External appearance: No external defects can be found in the visual inspection.
- 4) Electrode strength

No electrode detachment should be found when the device is pushed in two directions of X and Y with the force of 5.0N for 60 ± 1 seconds after soldering between copper plate and the electrodes. (Refer to figure)



5) Heat endurance test

Inductance deviation is within $\pm 5.0\%$ after reflow test be done for 3 times. according to the below chart, then the measurement shall be made in 2 hours after 1 hour storage under room ambient conditions



6) Vibration test

Inductance deviation is within $\pm 5.0\%$ after 2 hour sweeping vibration in each three directions, namely, forward and backward, up and down, right and left. The frequency is 10~55~10Hz and amplitude of 1 minute cycles is 1.5mm PP.

7) Shock test

Inductance deviation is within $\pm 5.0\%$ after the test with gum-block shock testing machine, once in each of the three perpendicular axis directions. The shock acceleration is 981m/s^2

DATA SHEET PAGE 6 / 1									
Part No	ECS-MPI2520R0/R1	Rev.	В						
humidity of 90~9	tion is within $\pm 5.0\%$ after 500 ± 12 hours test under the 15% and temperature of 60 ± 2 °C. and 1 hours storage the device is wiped with dry cloth.								
temperature of 10	e Storage test ion is within ±5.0% after 500±12hours test under the co 95±2℃ and 1 hours storage under room ambient conditi vithin the next 1 hour.		nich						
	ion is within $\pm 5.0\%$ after 500 ± 12 hours test under the could be and 1 hours storage under room ambient condition		nich						
for 30 minutes(Tra After 1000 cycles is tested within the 12) Board bent cha Inductance deviat	ect to -40℃ for 30 minutes hereafter it is subject to 105 ansition time is 1 minute maximum.) This constitutes on , it is then left in room temperature for I hour. After whic he next 1 hour and the inductance deviation is within	e cycle. h specimen ±5.0% n of the arro							
Specimen is subjective for 30 minutes(Transfer 1000 cycles), is tested within the second seco	ect to -40 °C for 30 minutes hereafter it is subject to 105 ansition time is 1 minute maximum.) This constitutes one, it is then left in room temperature for I hour. After which he next 1 hour and the inductance deviation is within aracteristic ion is within ± 5.0 %, after apply pressure in the direction at 0.5mm/s until bent with reaches 2mm and hold for	e cycle. h specimen ±5.0% n of the arro							
Specimen is subjective for 30 minutes(Trans After 1000 cycles), is tested within the sector within the	ect to -40 °C for 30 minutes hereafter it is subject to 105 ansition time is 1 minute maximum.) This constitutes one, it is then left in room temperature for I hour. After which he next 1 hour and the inductance deviation is within aracteristic ion is within ± 5.0 %, after apply pressure in the direction at 0.5mm/s until bent with reaches 2mm and hold for	e cycle. h specimen ±5.0% n of the arro 30 seconds	s						

	PAGE	7 / 10	
Part No	ECS-MPI2520R0/R1	Rev.	В
15) Humidity load I	ife test		

Inductance deviation is within $\pm 5.0\%$ and no structure and electric defects can be found after 1000 ± 12 hours test under the condition of relative humidity of $80\sim85\%$ and temperature of $85\pm2\%$ and allowable current loaded and 1 hour storage under room ambient conditions after which device is tested within the next 2 hours

16) High-temperature electrification test

The component is left in a constant temperature chamber of temperature 105 ± 2 °C applying the rated current for 1000 ± 12 hours after the soldering heat resistance test, and then the component is left at room temperature and normal humidity for 2 ± 1 hours. After that, any surface defects shouldn't be found and the rate of inductance against its initial value should be within $\pm5\%$

17) Low-temperature electrification test

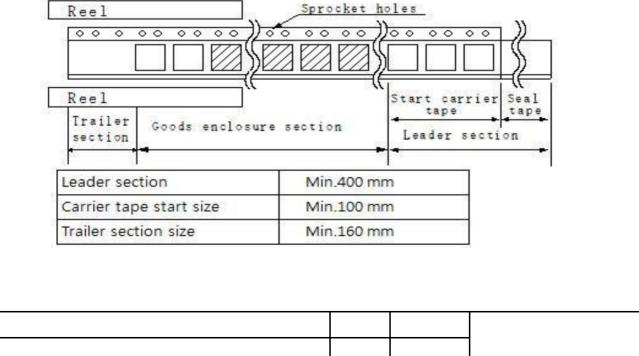
The component is left in a constant temperature chamber of temperature -40 ± 3 °C applying the rated current for 1000 ± 12 hours after the soldering heat resistance test, and then the component is left at room temperature and normal humidity for 2 ± 1 hours. After that, any surface defects shouldn't be found and the rate of inductance against its initial value should be within $\pm5\%$

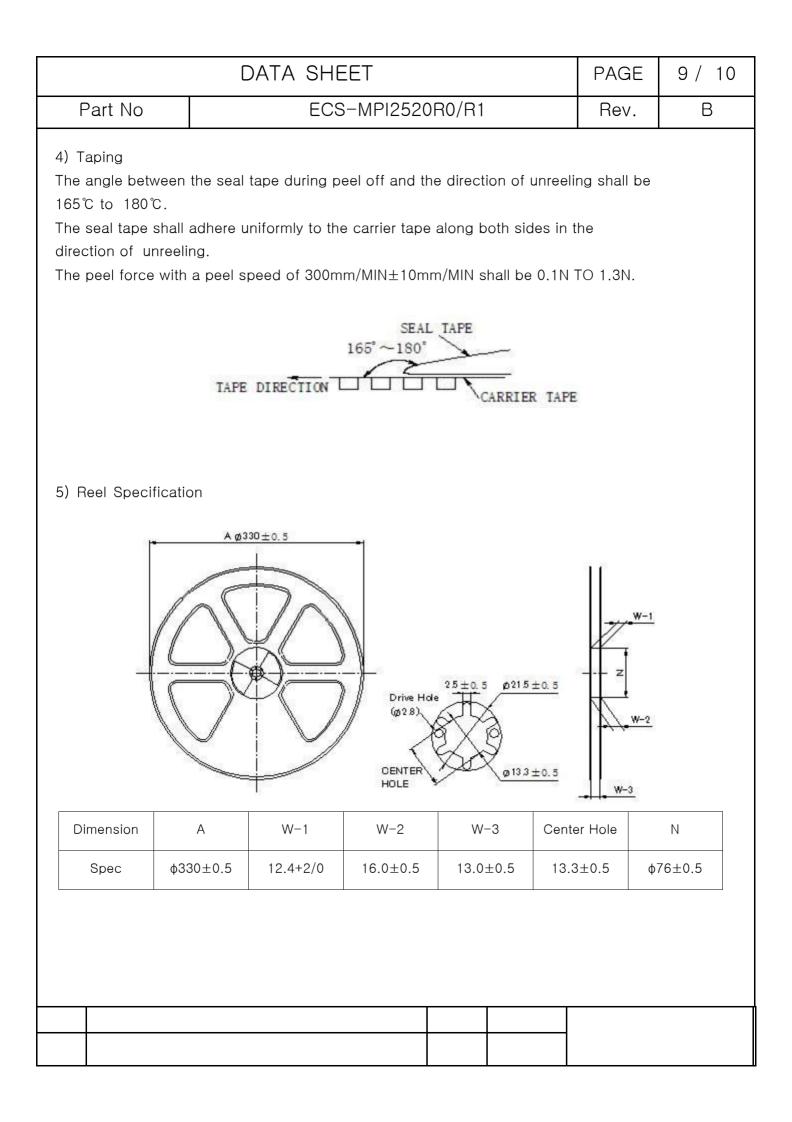
Application Notice / Handling

- 1) Temperature and humidity conditions: less than 40°C and 70% RH.
- 2) Products should be used within 6 months.
- 3) The packaging material should be kept where no chlorine or sulfur exists in the air.
- 4) Do not touch the electrodes (soldering terminals) with fingers as this may lead to deterioration of solderability.
- 5) The use of tweezers or vacuum pick-ups is strongly recommended for individual components.
- 6) Bulk handling should ensure that abrasion and mechanical shock are minimized

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		4

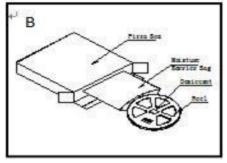
ata		ECS	-MPI2	2520R	80/R1			Rev.		В			
ata													
l (mm	7. Packaging Standard1) Packaging data												
<u> </u>	Component L(mm) W(mm) H(mm) Wt(g) Quantity									ntity			
2.70)	2.2	20		1.20		0.03		3,0	00			
$\begin{array}{c c} & & & \\ \hline \\$													
W A0		K0								P1			
.0± 2.3± 0.3 0.1	2.8± 0.1	1.3± 0.1	0.3± 0.1	4.0± 0.1	3.9± 0.1	1.75 ±0.1	1.5+ 0.1	1.5± 0.1	4.0± 0.1	2.0± 0.05			
\ \	<u>т</u> <u>ко</u> W <u>А0</u> 0± 2.3±	Т Р0 Ф Ф Ф КО М АО ВО 0± 2.3± 2.8±	Т Р Ф Ф Ф Ф Ф Ф Ф Ф Ф Ф Ф Ф Ф	$\begin{array}{c c} T & P0 & \hline \\ \hline$	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	$W = A0 = B0 = K0 = T = P = E = D0 = D1 = 0.3\pm 0.3\pm 0.3\pm 0.3\pm 0.3\pm 0.3\pm 0.3\pm 0.3\pm$	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$			

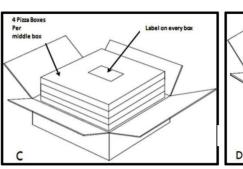




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6) Packing Materials





Packing Materials	B. Pizza Box			C. Middle Box			D. Large Box		
Dimension(mm)	L	W	Н	L	W	Н	L	W	Н
Dimension(mm)	335	335	50	355	355	230	720	370	255

7) Packing Specification

2middle box/Large box, 4Reel/Middle box, 1Reel/Pizza box, 7500pcs/Reel, Total 60000pcs(Large Box) Reel Dimensions : Ø 330 × 12(mm)

8. Environmental substances requirement

1) RoHs Compliance & Halogen Compliance

Test Items	Unit	Test Method	MDL	Results
Cd	mg/kg	With reference to IEC62321:2008, ICP	0.5	N.D.
Pb	mg/kg	With reference to IEC62321:2008, ICP	5	N.D.
Hg	mg/kg	With reference to IEC62321:2008, ICP	2	N.D.
Cr VI	mg/kg	With reference to IEC62321:2008, UV-VIS	1	N.D.
PBBs	mg/kg	With reference to IEC62321:2008, GC-MS	5	N.D.
PBDEs	mg/kg	With reference to IEC62321:2008, GC-MS	5	N.D.
Br	mg/kg	BS EN 14582:2007, IC	30	N.D.
CI	mg/kg	BS EN 14582:2007, IC	30	N.D.
F	mg/kg	BS EN 14582:2007, IC	30	N.D.
I	mg/kg	BS EN 14582:2007, IC	50	N.D.

Note

1) N.D. = Not detected(< MDL)

2) mg/kg = ppm

- 3) MDL = Method Detection Limit
- 4) Test instrument : SGS TEST KOREA

Mouser Electronics

Authorized Distributor

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ECS:

 ECS-MPI2520R1-100-R
 ECS-MPI2520R1-1R5-R
 ECS-MPI2520R1-6R8-R
 ECS-MPI2520R0-R47-R
 ECS

 MPI2520R0-1R0-R
 ECS-MPI2520R0-2R2-R
 ECS-MPI2520R0-3R3-R
 ECS-MPI2520R1-2R2-R
 ECS-MPI2520R0

 4R7-R
 ECS-MPI2520R0-1R5-R
 ECS-MPI2520R1-4R7-R
 ECS-MPI2520R1-5R6-R
 ECS-MPI2520R1-3R3-R
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 MPI2520R1-1R0-R
 ECS-MPI2520R1-1R0-R
 ECS-MPI2520R1-1R0-R
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